

<b>Notice of References Cited</b>	Application/Control No. 10/611,871	Applicant(s)/Patent Under Reexamination KONYA ET AL.	
	Examiner Daniel F. Hajnik	Art Unit 2671	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,464,358	10-2002	Shirakura et al.	353/7
*	B	US-2003/0164819	09-2003	Waibel, Alex	345/173
*	C	US-2002/0054032	05-2002	Aoki et al.	345/204
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	M	US-			

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**NON-PATENT DOCUMENTS**

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